

**Search Notes**

Application/Control No.

10/617,055

Examiner

Emeka Ebirim

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2166

**SEARCHED**

Class	Subclass	Date	Examiner
707	100	2/6/2006	EE
700	108	2/6/2006	EE
715	736	2/6/2006	EE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	2/6/2006	EE
Consulted Pham Khanh (Primary)	2/6/2006	EE